

<b>Notice of References Cited</b>		Application No. 08/889,440	Applicant(s) Takeuchi et al.			
		Examiner Hugh Jones	Group Art Unit 2123	Page 1 of 1		
<b>U.S. PATENT DOCUMENTS</b>						
	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	
A						
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<b>FOREIGN PATENT DOCUMENTS</b>						
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<b>NON-PATENT DOCUMENTS</b>						
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U	Husinsky et al.; "Fundamental aspects of SNMS for thin film characterization: experimental studies and computer simulations"; Thin Solid Films; pp. 289-309					1/1996
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